Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination
10/780,159	DEMEO ET AL.
Examiner	Art Unit
Vivian Chen	1773

	SEARCHED				
Class	Subclass	Date	Examiner		
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INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST text search printout	6/22/2007	NC/		
inventor search	6/22/2007	NC/		